

<b>Notice of References Cited</b>	Application/Control No. 10/577,018	Applicant(s)/Patent Under Reexamination YOSHIYA, SHUN	
	Examiner RICARDO E. LOPEZ	Art Unit 1786	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0154742	08-2003	Ooide, Ryosuke	63/38
	B	US-			
	C	US-			
	D	US-			
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